



GARY E. JOHNSON
GOVERNOR

State of New Mexico
ENVIRONMENT DEPARTMENT

Ground Water Quality Bureau
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PETER MAGGIORE
Secretary
PAUL R. RITZMA
Deputy Secretary

CERTIFIED MAIL - RETURN RECEIPT REQUESTED

April 10, 2001

David Neill
Philips Semiconductors
9201 Pan American Freeway NE
Albuquerque, NM 87113

RE: Response to Notice of Intent to Discharge for Investigation Derived Purge Water

Dear Mr. Neill:

The New Mexico Environment Department (NMED), Ground Water Quality Bureau (GWQB) has received your Notice of Intent (NOI), dated March 19, 2001, for the annual discharge of 1,648 gallons per year of investigation derived purge water from monitoring wells located near the Philips Semiconductors facility in accordance with Section 20.6.2.1201 of the Water Quality Control Commission (WQCC) Regulations. The facility is located at 9201 Pan American Freeway NE in Albuquerque in Section 12, T11N, R3E, Bernalillo County. The application satisfies the requirements of Section 20.6.2.1201 of the WQCC Regulations.

Based on the presently available information and effluent quality data in the NOI dated March 19, 2001, and in the amendment to the NOI dated April 4, 2001, the Ground Water Quality Bureau has determined that the proposed discharge is not likely to adversely impact ground water, and a discharge plan is not being required for this discharge as long as the discharge is as described.

The exempt discharge is briefly described as follows:

Investigation derived purge water is generated from ground water monitoring wells installed to monitor ground water conditions associated with the former Coronado Municipal Landfill located near the Philips Semiconductors facility. The ground water monitoring is conducted as part of a Resource Conservation and Recovery Act (RCRA) Facility Investigation. The ground water discharge will be from three existing and three future Philips Semiconductors monitoring wells

Mr. David Neill

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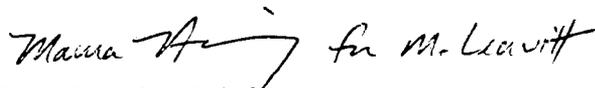
(MW-1, MW-2, MW-4, MW-5, MW-6 and MW-7), and eight City of Albuquerque monitoring wells (NCLF-2, NCLF-3, NCLF-4, NCLF-5, NCLF-6, NCLF-7, NCLF-8, and NCLF-9). The yearly purge water volume produced during quarterly and annual sampling will be approximately 1,648 gallons. Purge water will be discharged to the ground surface adjacent to each monitoring well. Purge water generated from a monitoring well which showed contaminant concentrations above WQCC 20.6.2.3103 standards the prior sampling event and purge water generated prior to initial testing of the future monitoring wells will be containerized and characterized prior to discharge. If analytical results show it is below WQCC 20.6.2.3103 standards, then the purge water will be discharged to the ground. If above WQCC 20.6.2.3103 standards, the water will be placed in the waste stream at the plant. All purge water generation will be tracked using sampling logbooks.

Although a discharge plan is not being required for this discharge at this time, you are not relieved of liability should your operation result in actual pollution of surface or ground waters. Further, this decision by the NMED does not relieve you of your responsibility to comply with any other applicable federal, state, and/or local laws and regulations, such as zoning requirements, plumbing codes and nuisance ordinances.

If at some time in the future you intend to change the amount, the character, or location of your discharge so that it will not be as described, or if observation or monitoring shows that the discharge is not as described, you must file a new request for exemption with the Ground Water Pollution Prevention Section (GWPPS).

If you have any questions, please contact either Susan von Gonten of the GWPPS staff at 827-0018 or Maura Hanning, Program Manager of the GWPPS at 827-2900.

Sincerely,



Marcy Leavitt, Chief
Ground Water Quality Bureau

ML:SvG/svg

xc: Thomas Skibitski, District Manager, NMED District I (via e-mail)
Kirby Olson, HWB
David Paulson, CHMM, Environmental Section Head, Philips Semiconductors
NOI File

Code#	System Name	ID	Source Name	Date Sampled	Contaminant	Note	Result	+/-	Mdl	Units
37326	EL DORADO UTILITIES	1	WELL # 1 (RG-18528)	13-nov-1995	RADON		455	26	14	PCI/L
				30-aug-1993	RADON		564	32	13	PCI/L
				30-aug-1993	RADON		592	33	14	PCI/L
		2	WELL # 2 (RG-18529)	12-apr-1994	RADON		323	20	12	PCI/L
				13-nov-1995	RADON		297	19	14	PCI/L
		3	WELL # 3 (RG-18543)	12-apr-1994	RADON		1166	62	12	PCI/L
				13-nov-1995	RADON		993	37	13	PCI/L
				30-aug-1993	RADON		1203	66	14	PCI/L
		4	WELL # 4 (RG-18550)	12-apr-1994	RADON		1400	74	12	PCI/L
				13-nov-1995	RADON		1510	79	14	PCI/L
				30-aug-1993	RADON		1620	84	14	PCI/L
		5	WELL # 5 (RG-18515)	04-apr-1995	RADON		1620	85	17	PCI/L
		6	WELL # 6 (RG-18571)	04-apr-1995	RADON		473	19	17	PCI/L
				06-nov-2000	RADON		1461		18	PCI/L
30-aug-1993	RADON				424	25	14	PCI/L		
7	WELL # 7 (RG-18595)	13-nov-1995	RADON		691	38	14	PCI/L		
8	WELL # 8 (RG-18531)	01-sep-1993	RADON		2160	110	16	PCI/L		
		13-nov-1995	RADON		1020	54	14	PCI/L		
9	WELL # 9 (RG-18556)	01-sep-1993	RADON		258	18	16	PCI/L		
		13-nov-1995	RADON		219	15	14	PCI/L		
12	WELL #12	13-nov-1995	RADON		1500	78	14	PCI/L		
13	WELL 13	01-may-2000	RADON		1221		13.4	PCI/L		
14	WELL 14	01-may-2000	RADON		507		13.4	PCI/L		